

<b>Notice of References Cited</b>	Application/Control No. 10/520,042	Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner Tiffany A. Fetzner	Art Unit 2859	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004045238	02-2004	Japan	SUN et al.	
	O	WO 2004008126 A1 ✓	01-2004	World Intellect	SUN et al.	
	P					
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✱	U	Son Yu et al., article "Dielectric Loss in C60 Films Observed by Direct Coupling with Electromagnetic Fields" Kyushu Institute of Technology March 2002, Vol. 49, No. 2, page 582. under document identifier 29p-YL-17 0226 on page 582.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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